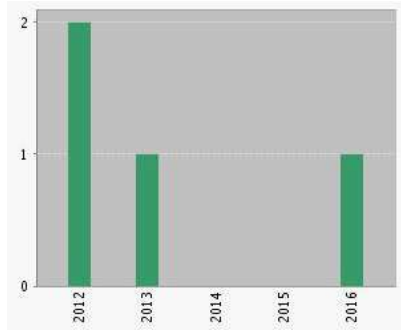


**Citation Report: 4**

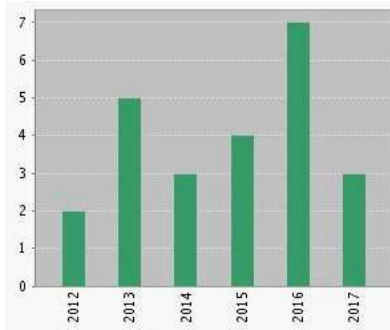
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	Use the checkboxes to remove individual items from this Citation Report or restrict to items published between <input type="text" value="2012"/> and <input type="text" value="2016"/> <input type="button" value="Go"/>							
<input checked="" type="checkbox"/>	1. Evaluating reliability of WSN with sleep/wake-up interfering nodes By: Distefano, Salvatore INTERNATIONAL JOURNAL OF SYSTEMS SCIENCE Volume: 44 Issue: 10 Pages: 1793-1806 Published: OCT 1 2013	5	3	4	7	3	24	4.00
<input checked="" type="checkbox"/>	2. Evaluating wireless sensor node longevity through Markovian techniques By: Bruno, Dario; Distefano, Salvatore; Longo, Francesco; et al. COMPUTER NETWORKS Volume: 56 Issue: 2 Pages: 521-532 Published: FEB 2 2012	3	0	2	4	3	12	2.40
<input checked="" type="checkbox"/>	3. Reliability of Wireless Sensor Network: Hotspot and Critical Challenges By: Yao, Nan; Wang, Shaoping; Shang, Yaoxing; et al. Book Group Author(s): IEEE Conference: 10th IEEE International Conference on Industrial Informatics (INDIN) Location: Beijing, PEOPLES R CHINA Date: JUL 25-27, 2012 Sponsor(s): IEEE; Beihang Univ 2012 10TH IEEE INTERNATIONAL CONFERENCE ON INDUSTRIAL INFORMATICS (INDIN) Book Series: IEEE International Conference on Industrial Informatics INDIN Pages: 1262-1266 Published: 2012	0	0	0	1	0	1	0.17
<input checked="" type="checkbox"/>	4. INTRODUCING PROBABILISTIC MODELS FOR REDUNDANT SYSTEM RELIABILITY By: Babagana, Mansur; Gimba, Bello; Yusuf, Ibrahim OPERATIONS RESEARCH AND DECISIONS Volume: 26 Issue: 1 Pages: 5-18 Published: 2016	0	0	0	0	0	0	0.00